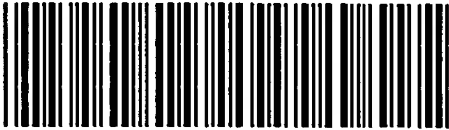


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/019,864	BITTROFF ET AL.	
	Examiner	Art Unit	
	Quynh H. Nguyen	2642	

SEARCHED			
Class	Subclass	Date	Examiner
379	196 211.03	12/21/2005	QN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
searched East	12/21/2005	QN
inventor searched through PALM database	12/21/2005	QN